

**IN74LV245**

**OCTAL BUS TRANSCEIVER; 3-State**

The IN74LV245 is a low-voltage Si-gate CMOS device and is pin and function compatible with IN74HCT245.

The IN74LV245 is an octal transceiver featuring non-inverting 3-state bus compatible outputs in both send and receive directions. The IN74LV245 features an output enable ( $\overline{OE}$ ) input for easy cascading and a send/receive (DIR) input for direction control.  $\overline{OE}$  controls the outputs so that the buses are effectively isolated.

- Output voltage levels are compatible with input levels of CMOS, NMOS and TTL ICs
- Supply voltage range: 1.2 to 3.6 V
- Low input current: 1.0  $\mu$ A; 0.1  $\mu$ A at T = 25 °C
- Output Current: 8 mA at  $V_{CC} = 3.0$  V
- High Noise Immunity Characteristic of CMOS Devices

N SUFFIX  
PLASTIC DIP

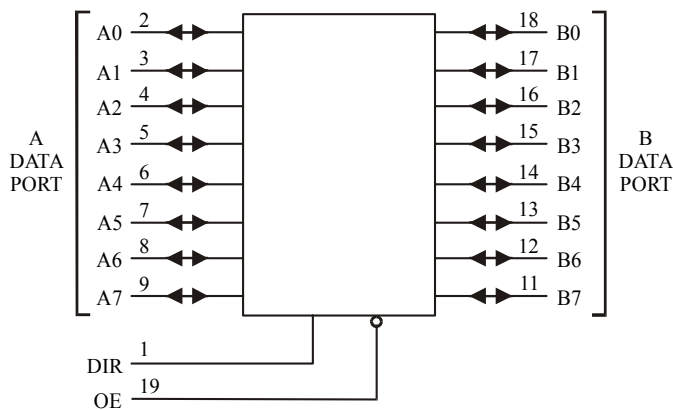
DW SUFFIX  
SO

**ORDERING INFORMATION**

**IN74LV245N** Plastic DIP  
**IN74LV245DW** SOIC  
**IZ74LV245** chip

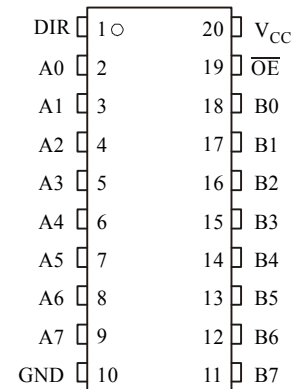
$T_A = -40^\circ$  to  $125^\circ$  C for all packages

**LOGIC DIAGRAM**



PIN 20 =  $V_{CC}$   
 PIN 10 = GND

**PIN ASSIGNMENT**



**FUNCTION TABLE**

Inputs		Inputs/outputs	
$\overline{OE}$	DIR	A	B
L	L	A=B	input
L	H	input	B=A
H	X	Z	Z

H= high level  
 L = low level  
 X = don't care  
 Z = high impedance

**MAXIMUM RATINGS\***

Symbol	Parameter	Value	Unit
V <sub>CC</sub>	DC supply voltage	-0.5 to +5.0	V
I <sub>IK</sub> * <sup>1</sup>	DC Input diode current	±20	mA
I <sub>OK</sub> * <sup>2</sup>	DC Output diode current	±50	mA
I <sub>O</sub> * <sup>3</sup>	DC Output source or sink current	±35	mA
I <sub>CC</sub>	DC V <sub>CC</sub> current	±70	mA
I <sub>GND</sub>	DC GND current	±70	mA
P <sub>D</sub>	Power dissipation per package: * <sup>4</sup> Plastic DIP SO	750 500	mW
T <sub>stg</sub>	Storage Temperature	-65 to +150	°C
T <sub>L</sub>	Lead Temperature, 1.5 mm (Plastic DIP Package), 0.3 mm (SO Package) from Case for 4 Seconds	260	°C

\*Maximum Ratings are those values beyond which damage to the device may occur.

Functional operation should be restricted to the Recommended Operating Conditions.

\*<sup>1</sup> V<sub>I</sub> < -0.5 V or V<sub>I</sub> > V<sub>CC</sub> + 0.5 V.

\*<sup>2</sup> V<sub>O</sub> < -0.5 V or V<sub>O</sub> > V<sub>CC</sub> + 0.5 V.

\*<sup>3</sup> -0.5 V < V<sub>O</sub> < V<sub>CC</sub> + 0.5 V.

\*<sup>4</sup> Derating - Plastic DIP: - 12 mW/°C from 70° to 125°C

SO Package: : - 8 mW/°C from 70° to 125°C

**RECOMMENDED OPERATING CONDITIONS**

Symbol	Parameter	Min	Max	Unit
V <sub>CC</sub>	DC Supply Voltage	1.2	3.6	V
V <sub>I</sub>	Input Voltage	0	V <sub>CC</sub>	V
V <sub>O</sub>	Output Voltage	0	V <sub>CC</sub>	V
T <sub>A</sub>	Operating Temperature, All Package Types	-40	+125	°C
t <sub>r</sub> , t <sub>f</sub>	Input Rise and Fall Time (Figure 1)			
	V <sub>CC</sub> = 1.2 V	0	1000	ns
	V <sub>CC</sub> = 2.0 V	0	700	
	V <sub>CC</sub> = 3.0 V	0	500	
	V <sub>CC</sub> = 3.6 V	0	400	

This device contains protection circuitry to guard against damage due to high static voltages or electric fields. However, precautions must be taken to avoid applications of any voltage higher than maximum rated voltages to this high-impedance circuit. For proper operation, V<sub>IN</sub> and V<sub>OUT</sub> should be constrained to the range GND ≤ (V<sub>IN</sub> or V<sub>OUT</sub>) ≤ V<sub>CC</sub>.

Unused inputs must always be tied to an appropriate logic voltage level (e.g., either GND or V<sub>CC</sub>). Unused outputs must be left open.

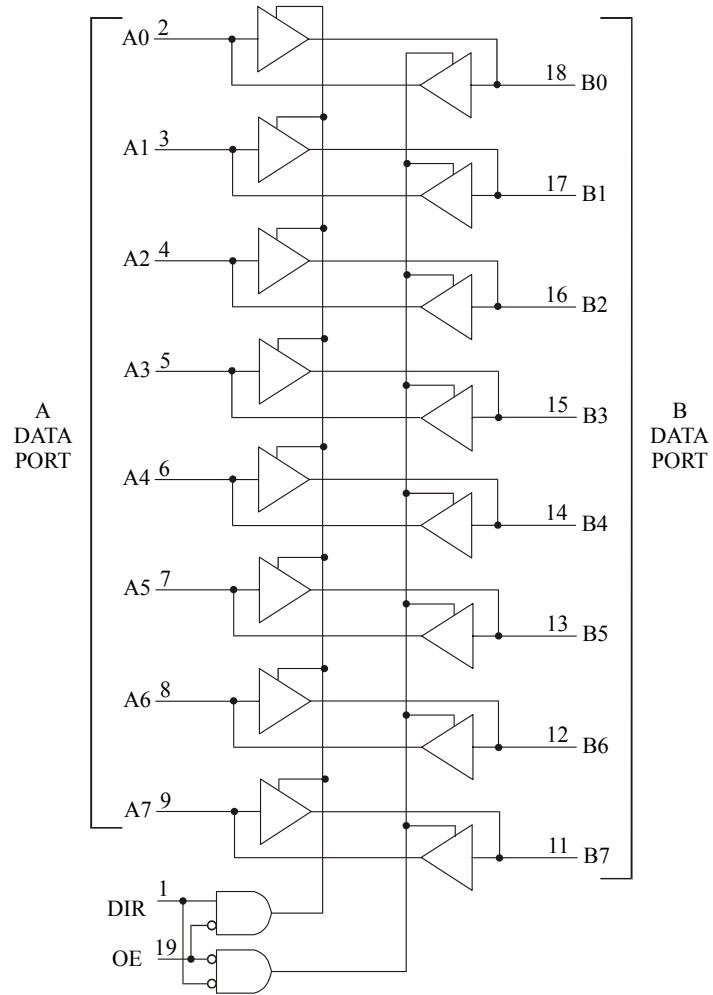
## DC ELECTRICAL CHARACTERISTICS (Voltages Referenced to GND)

Symbol	Parameter	Test conditions	V <sub>CC</sub> V	Guaranteed Limit						Unit
				25°C		-40°C to 85°C		125°C		
				min	max	min	max	min	max	
V <sub>IH</sub>	HIGH level input voltage		1.2	0.9	-	0.9	-	0.9	-	V
			2.0	1.4	-	1.4	-	1.4	-	
			3.0	2.1	-	2.1	-	2.1	-	
			3.6	2.5	-	2.5	-	2.5	-	
V <sub>IL</sub>	LOW level input voltage		1.2	-	0.3	-	0.3	-	0.3	V
			2.0	-	0.6	-	0.6	-	0.6	
			3.0	-	0.9	-	0.9	-	0.9	
			3.6	-	1.1	-	1.1	-	1.1	
V <sub>OH</sub>	HIGH level output voltage	V <sub>I</sub> = V <sub>IH</sub> or V <sub>IL</sub> I <sub>O</sub> = -50 μA	1.2	1.1	-	1.0	-	1.0	-	V
			2.0	1.92	-	1.9	-	1.9	-	
			3.0	2.92	-	2.9	-	2.9	-	
			3.6	3.52	-	3.5	-	3.5	-	
		3.0	2.48	-	2.34	-	2.20	-	V	
V <sub>OL</sub>	LOW level output voltage	V <sub>I</sub> = V <sub>IH</sub> or V <sub>IL</sub> I <sub>O</sub> = 50 μA	1.2	-	0.09	-	0.1	-	0.1	V
			2.0	-	0.09	-	0.1	-	0.1	
			3.0	-	0.09	-	0.1	-	0.1	
			3.6	-	0.09	-	0.09	-	0.09	
		3.0	-	0.33	-	0.4	-	0.5	V	
I <sub>I</sub>	Input current	V <sub>I</sub> = V <sub>CC</sub> or 0 V	*	-	±0.1	-	±1.0	-	±1.0	μA
I <sub>OZ</sub>	Three state leakage current	3-state outputs V <sub>I</sub> (19) = V <sub>IH</sub> V <sub>O</sub> = V <sub>CC</sub> or 0 V	1.2 *	-	±0.5	-	±5	-	±10	μA
I <sub>CC</sub>	Supply current	V <sub>I</sub> = V <sub>CC</sub> or 0 V I <sub>O</sub> = 0 μA	*	-	8.0	-	80	-	160	μA

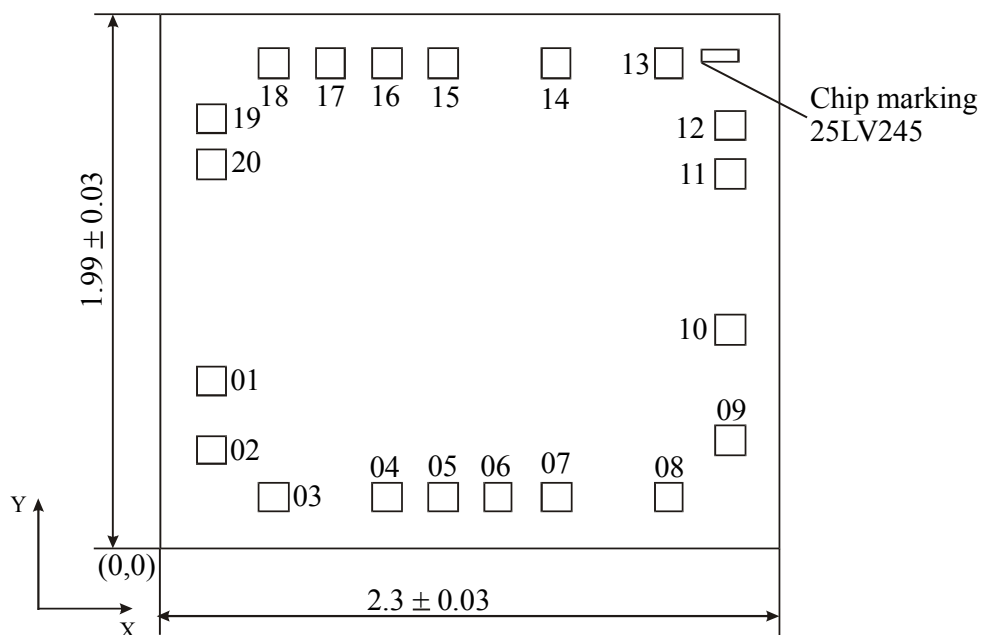
\* V<sub>CC</sub> = 3.3 ± 0.3 V



EXPANDED LOGIC DIAGRAM



## CHIP PAD DIAGRAM



**Location of marking (mm):** left lower corner  $x=2.010$ ,  $y=1.810$ .

**Chip thickness:**  $0.46 \pm 0.02$  mm.

## PAD LOCATION

Pad No	Symbol	Location (left lower corner), mm		Pad size, mm
		X	Y	
01	DIR	0.140	0.573	0.108 x 0.108
02	A0	0.140	0.315	0.108 x 0.108
03	A1	0.370	0.140	0.108 x 0.108
04	A2	0.790	0.140	0.108 x 0.108
05	A3	1.000	0.140	0.108 x 0.108
06	A4	1.200	0.140	0.108 x 0.108
07	A5	1.417	0.140	0.108 x 0.108
08	A6	1.833	0.140	0.108 x 0.108
09	A7	2.060	0.354	0.108 x 0.108
10	GND	2.060	0.760	0.108 x 0.108
11	B7	2.060	1.340	0.108 x 0.108
12	B6	2.060	1.520	0.108 x 0.108
13	B5	1.833	1.750	0.108 x 0.108
14	B4	1.415	1.750	0.108 x 0.108
15	B3	1.000	1.750	0.108 x 0.108
16	B2	0.790	1.750	0.108 x 0.108
17	B1	0.580	1.750	0.108 x 0.108
18	B0	0.370	1.750	0.108 x 0.108
19	$\overline{OE}$	0.140	1.544	0.108 x 0.108
20	V <sub>CC</sub>	0.140	1.375	0.108 x 0.108

Note: Pad location is given as per metallization layer